## Application/Control No. O9/754,277 Examiner Luz L. Alejandro Applicant(s)/Patent Under Reexamination SAWAYAMA, TAKAYOSHI Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,885,352	03-1999	Miyajima, Hideshi	118/708
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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